



REPORT No. : SZ19080340E01

TEST REPORT

Applicant : SHANGHAI MOUNTAIN VIEW SILICON CO., LTD

PRODUCT NAME : MV_BP10xx PCB Antenna

MODEL NAME : MV_BP10

TRADE NAME : MVSILICON

BRAND NAME : MVSILICON

STANDARD(S) : ANSI/IEEE Std 149-2008

RECEIPT DATE : 2019-08-30

TEST DATE : 2019-09-02

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MORLAB

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Change History		
Version	Date	Reason for change
1.0	2019-10-15	First edition



1. Technical Information

Note: Provide by manufacturer.

1.1. Manufacturer and Factory Information

Applicant:	SHANGHAI MOUNTAIN VIEW SILICON CO., LTD
Applicant Address:	Suite 4C, Building 3, 1238 Zhangjiang Road, Pudong New District, Shanghai, China
Manufacturer:	SHANGHAI MOUNTAIN VIEW SILICON CO., LTD
Manufacturer Address:	Suite 4C, Building 3, 1238 Zhangjiang Road, Pudong New District, Shanghai, China

1.2. Equipment Under Test (EUT) Description

Wireless Type	N/A
Frequency	N/A

2. Test Results

2.1. Applied Reference Documents

Leading reference documents for testing:

No.	Identity	Document Title
1	ANSI/IEEE Std 149-2008	IEEE Standard Test Procedures for Antennas

2.2. Test Conditions

Test Environment Conditions:

Relative Humidity:	25 ... 75 %
Temperature:	+10 °C to +30 °C

2.3. Test Results lists

2.3.1. Gain

Frequency	Gain(dBi)
2400MHz	2.81
2410MHz	2.74
2420MHz	3.38
2430MHz	2.73
2440MHz	1.01
2450MHz	1.26
2460MHz	1.50
2470MHz	1.49
2480MHz	1.42
2490MHz	0.36
2500MHz	0.33

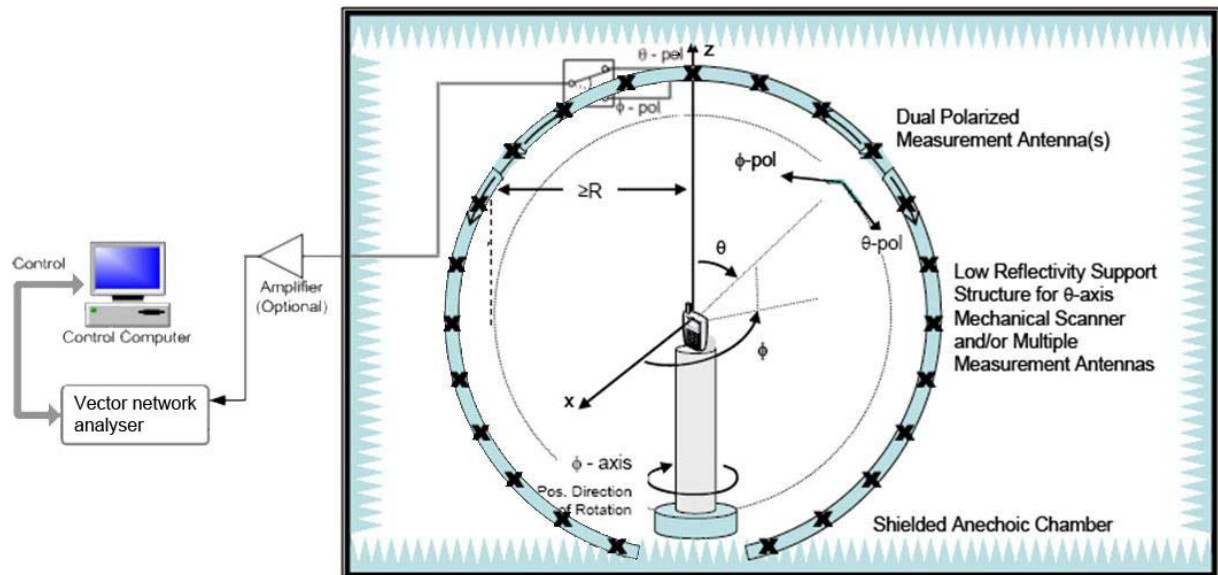


2.3.2.Return Loss/VSWR/Input Impedance

Frequency	Return Loss (dB)	VSWR	Input Impedance(Ω)
2400MHz	-7.23	2.53	25.37
2440MHz	-6.47	2.80	17.99
2450MHz	-6.22	2.90	17.18
2480MHz	-5.18	3.44	15.55
2500MHz	-4.56	3.89	15.48

Annex A Photographs

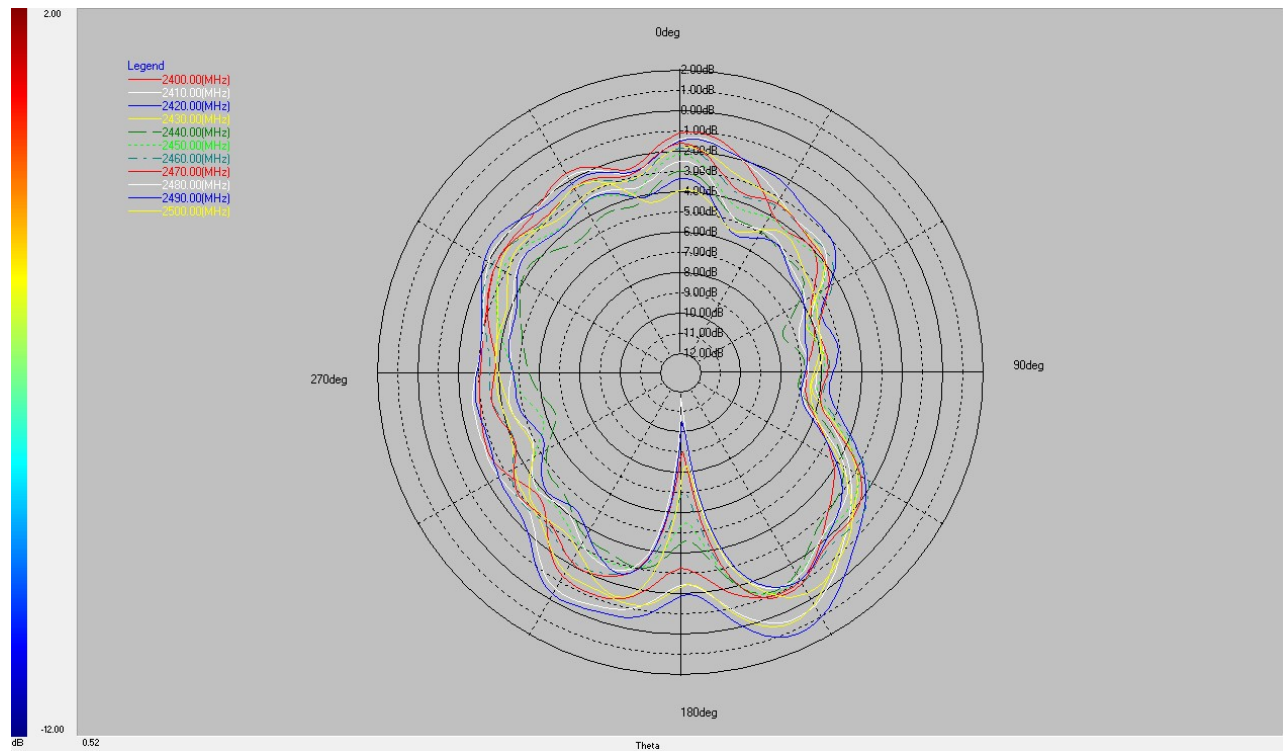
1. Test Setup



Annex B Figures

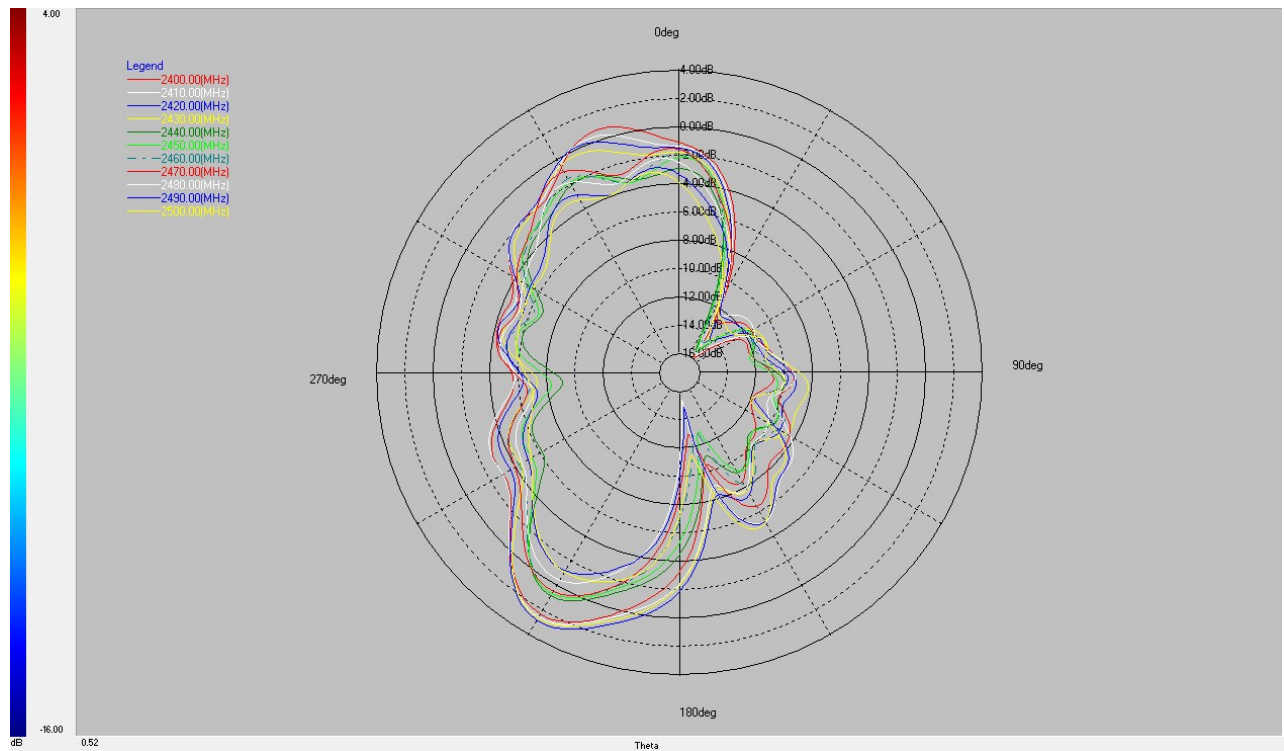
1. 2D Radiation Pattern

Phi=0°

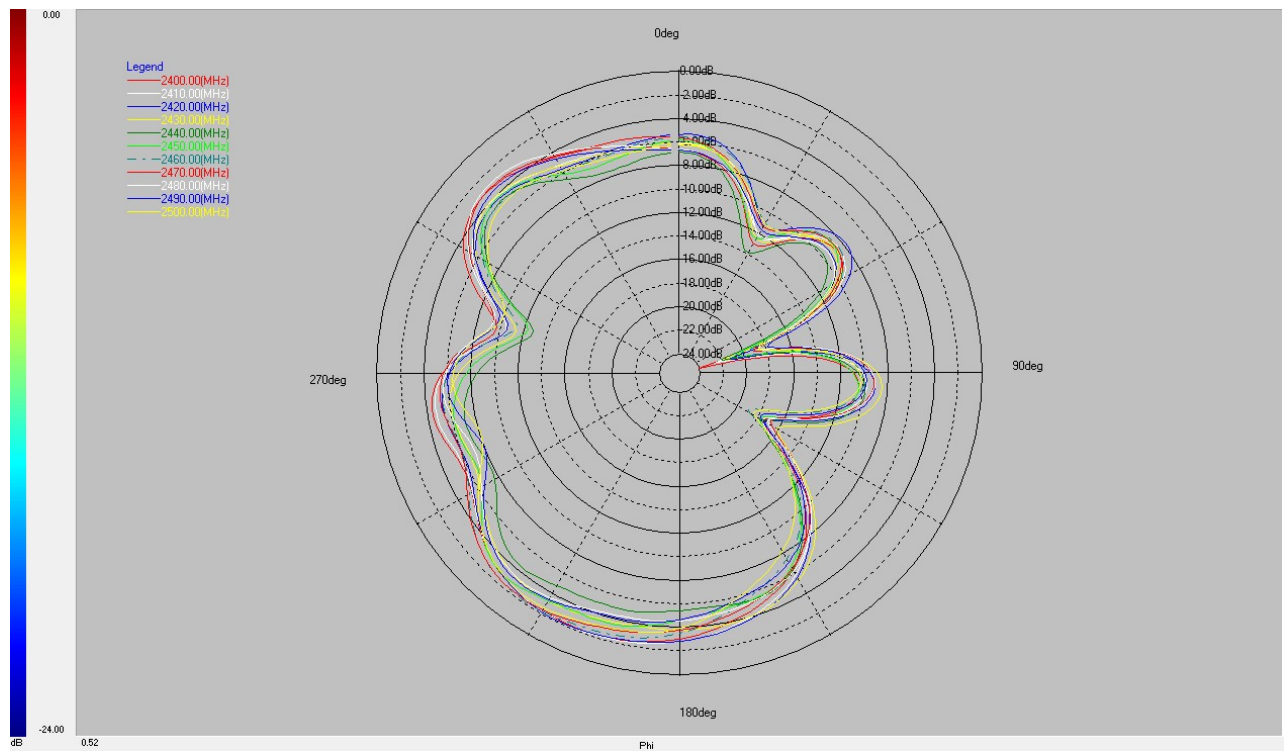




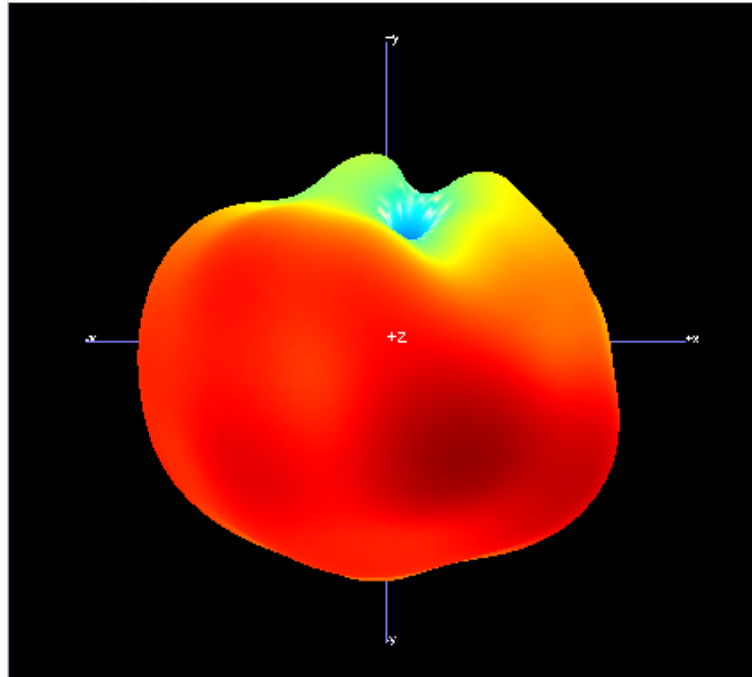
Phi=90°



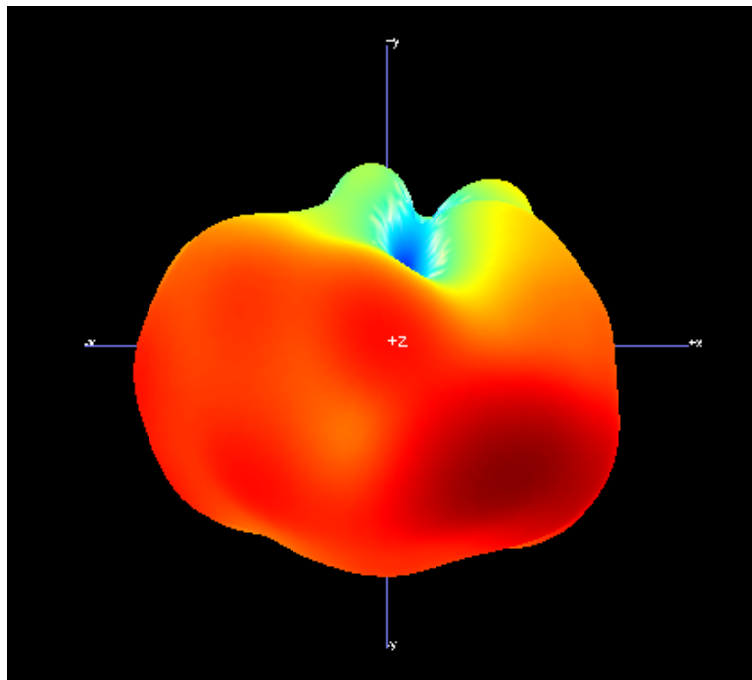
Theta=90°



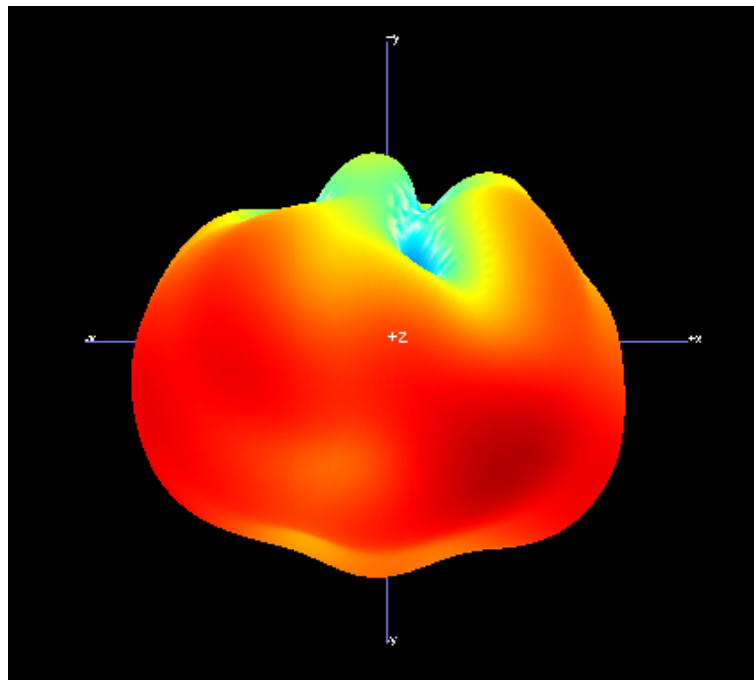
2. 3D Radiation Pattern



2400MHz

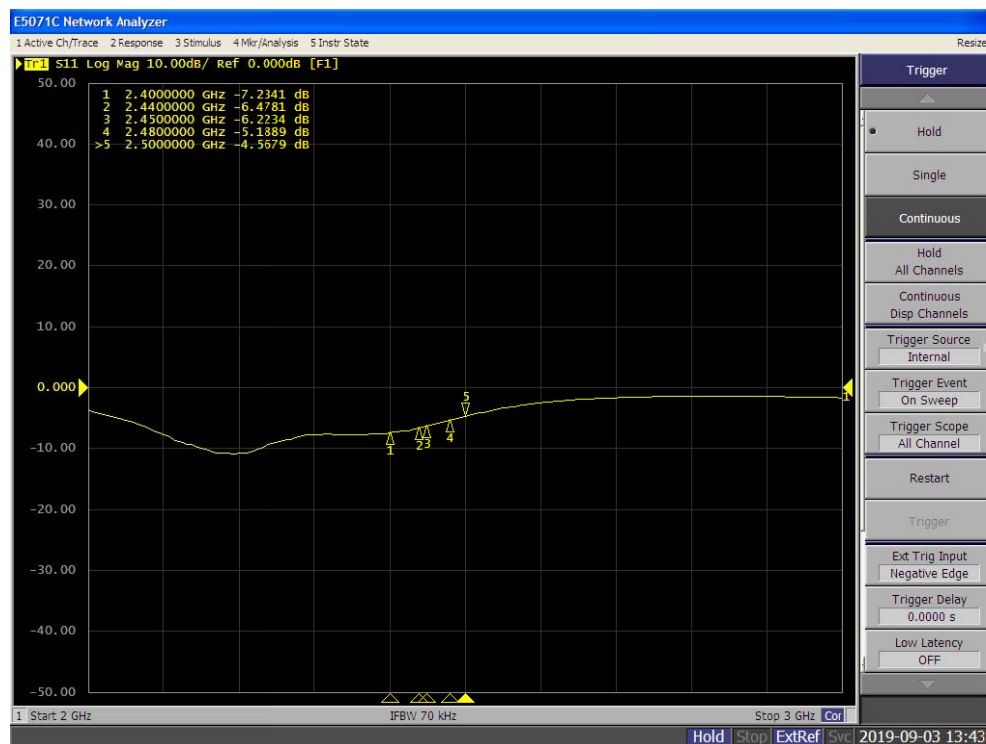


2450MHz



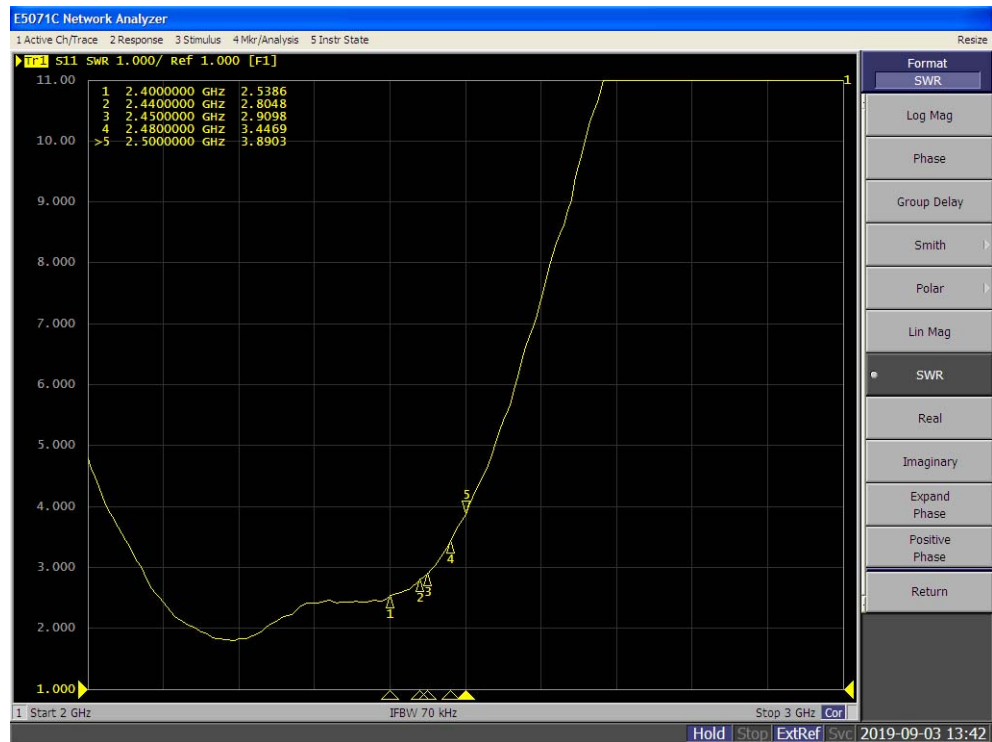
2500MHz

3. Return Loss





4. VSWR



5. Input Impedance

